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SERIAL DECEIVED ATTORNEY DOCKET NO. Form PTO-1449 AUS9-2000-0546-US1 IST OF PRIOR ART CITED APR 2 2 2004 BY APPLICANT ( several sheets if necessary) Technology Center 2100 APPLICANT Beukema et al. GROUP ART UNIT 2112 FILING DATE December 7, 2000 U.S. PATENT DOCUMENTS **PUBLICATION EXAMINER DOCUMENT** INVENTOR NAME CLASS/ FILING INITIAL NO. DATE SUBCLASS DATE King 358/1.14 Dec. 22, 1998 6,529,286 B1 Mar. 4, 2003 6,330,555 B1 Dec. 11, 2001 Weber 707/2 Feb. 19, 1999 مارا 370/55 May 12, 1989 5.185.736 Feb. 9, 1993 Tyrrell et al. BA W Pearlman et al. 382/240 Sep. 25, 2002 BB 6,674,911 B1 Jan. 6, 2004 Oct. 3, 1994 5,617,537 Apr. 1, 1997 Yamada et al. 395/200.01 BC wh 395/325 Mar. 15, 1990 Jun. 8, 1993 Farrell et al. BD 5,218,680 709/221 Nov. 14, 1997 6.098,098 Aug. 1, 2000 Sandahl et al. BE Dec. 17, 2002 Pelissier et al. 370/389 Jun. 1, 1999 BF 6,496,503 B1 Aug. 21, 1990 Lee et al. Nov. 14, 1988 364/513 BG 4.951.225 Jul. 31, 2001 709/223 Dec. 11, 1998 вн 6,269,396 B1 Shah et al. Oct. 28, 1997 709/238 ВI 6,032,191 Feb. 29, 2000 Chowdhury et al. 370/230 Mar. 31, 1997 Apr. 24, 2001 Gerardin et al. BJ 6,222,822 B1 BK 5,513,368 Apr. 30, 1996 Garcia, Jr. et al. 395/842 Jul. 16, 1993 370/60 Jan. 5, 1994 Mar. 28, 1995 Cieslak et al. BL 5,402,416 370/389 May 3, 1996 Apr. 1, 1997 Murayama et al. BM 5,617,424 709/238 Mar. 15, 2002 2002/0133620 Sep. 19, 2002 Krause FOREIGN PATENT DOCUMENTS **PUBLICATION** CLASS/ **TRANSLATION** COUNTRY **EXAMINER** DOCUMENT **SUBCLASS** YES NO DATE INITIAL NO. X BO WO 00/72159 Nov. 30, 2000 WIPO G06F 13/00 OTHER PRIOR ART (Inducting author, title, date, pertinent page, etc.) Nehmer et al, "A Fault Tolerance Approach for Distributed ISDN Control Systems", ACM SIGOPS European Workshop, Proceedings of the fourth workshop on ACM SIGOPS European workshop, 1990, Bologna, Italy, 1990, pp. 1-4. DATE CONSIDERED EXAMINER 7111 184 lm EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP § 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.